

heater of each sensor element along the periphery of the sensor element, temperature gradients are minimized.

The support for the catalyst and the resistors is the polysilicon structure. A silicon nitride encapsulation is applied to the polysilicon structure for protection during the fabrication of the paired sensing elements. Back-etching isolates the polysilicon plate from the silicon frame surrounding the paired elements of the sensor. The polysilicon elements can be accurately micromachined using reactive ion etching (RIE), a well known process, thereby adapting the process to high volume manufacturing. Further, the size of the sensing elements can be made larger than the corresponding elements of prior art sensors that may comprise more fragile membrane structures made of dielectric films.

The etching process isolates the sensing elements by providing through openings to the back surface of the sensor. The openings provide thermal isolation of the sensing elements and permit the reactants to diffuse through the sensor to the back surface. Therefore, the sensitivity can be increased by depositing the catalyst both on the top and bottom surfaces of the sensor plate.

BRIEF DESCRIPTION OF THE FIGURES OF THE DRAWINGS

FIG. 1 is an isometric view of a microcalorimeter including polysilicon plates supported on a bulk silicon frame with metal resistors, such as platinum resistors, that serve as heaters and temperature sensing elements.

FIG. 2A is a schematic cross-sectional view of the polysilicon plate, the silicon frame and the silicon nitride layer between the silicon and the polysilicon, which are assembled in earlier steps of the fabrication process.

FIG. 2B is a schematic cross-sectional view of the components of the sensor element after the second step in the fabrication process involving polysilicon patterning and a passivation of silicon nitride.

FIG. 2C is a schematic cross-sectional view of the components of the sensor during a third step in the fabrication process involving platinum deposition and patterning.

FIG. 2D is a schematic cross-sectional view of the components of the sensor during a fourth fabrication step involving a passivation layer of silicon nitride.

FIG. 2E illustrates the fifth step in the fabrication process, which involves selective etching of the passivation applied in the step illustrated in FIG. 2D.

FIG. 2F is a schematic cross-sectional view of a finished sensor following a deep etch of the silicon base.

FIG. 3 is a graph showing the relationship between the resistance difference of the platinum resistors in the active and in the reference temperature sensing elements plotted as a function of four different combustible gas concentrations by volume, together with the corresponding average temperature rise produced by the reaction of each of the gases.

PARTICULAR DESCRIPTION OF THE INVENTION

In FIG. 1, we have shown a sensor comprising a bulk silicon frame 10 and a polysilicon layer 12 attached to one side of the frame 10. Located within the boundaries of the polysilicon layer are two polysilicon plates 14 and 16. These are located in openings 18 and 20, respectively, in layer 12. Plate 14 is held in place within the opening 18 by four polysilicon arms 22, 24, 26 and 28

extending from the polysilicon layer 12. The arms are integral with layer 12.

The polysilicon plate 16 of the companion sensor is suspended in opening 20 and is held in place by four polysilicon arms shown at 30, 32, 34 and 36. These correspond to the polysilicon arms for the plate 14.

Platinum resistors are deposited on the polysilicon layer 12. Platinum conductor resistor 38 forms a heater resistance element and is provided with a heater terminal 40. A terminal 42 for the heater resistance element 38 is located also on the polysilicon layer. The resistance element 38 follows a circuitous path around the holes or openings for the sensor element plate 14 and over the sensor plate supporting arms 22 and 28. The mid-region of the resistor 38 surrounds the periphery of the plate 14, as shown at 44. The mid-region 44 of the resistor thus forms a heater element circuit between terminals 40 and 42.

A temperature-sensing resistance in the form of a metallic resistor, preferably a platinum resistor, is shown at 46. Resistor 46 extends over the arm 26. The intermediate portion of the resistor 46 is located on the inboard region of the plate 14, as shown at 48. The portion 48 thus forms a part of a complete circuit between resistor terminal 50 and resistor terminal 52 carried on the polysilicon layer 12.

The polysilicon plate 16 of the companion sensor element also has a heater resistor 54 with an intermediate portion 56 that surrounds the periphery of the plate 16. Intermediate portion 56 forms a part of a complete heater resistance circuit for the resistor 54 extending from heater terminal 58 to heater terminal 60.

The central region of the plate 16 carries intermediate portion 64 of resistor 62. The sensor resistor terminals for the resistor 62 are shown at 66 and 68. These correspond to terminals 50 and 52 of the companion sensor element.

A catalyst layer 70 is deposited on the polysilicon plate 16. No catalyst, however, is applied to the companion polysilicon plate 14.

It is thus seen that each sensor plate supports two platinum resistors. Resistors 38 and 54 serve as heaters, and the resistors 46 and 62 serve as thermometers. The location of the heater pattern at the periphery of the plates, with the thermometer pattern at the central part of each of the plates, provides uniform heat distribution for each of the plates. The high thermal conductivity of the polysilicon material compensates for thermal energy loss to the ambient gases, thus minimizing the temperature drop at the center of each of the plates. The resistance of the temperature sensing conductor is preferably ten times larger than that of the electrical interconnects that are provided by extending the platinum resistor material on the four polysilicon arms for each of the sensor element plates.

As seen in FIGS. 2A through 2F, the plates and the platinum resistors are covered by a layer of silicon nitride for passivation with the exception of the terminals, where electrical contact can be established by wire bonding.

Referring next to FIGS. 2A through 2F, we have illustrated the various fabrication steps that are carried out in the manufacture of the sensor. FIG. 2A shows the starting materials, which comprise a bulk silicon frame 10. A polysilicon layer 12 is deposited on top of the silicon frame 10, and a corresponding layer 72 is deposited on the other side of the frame 10. As indicated also in FIG. 2A, the frame 10 is passivated on both sides by